

# HiPerFET™ Power MOSFET

**IXFN38N100Q2**

N-Channel Enhancement Mode

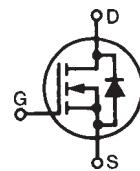
Avalanche Rated, Low  $Q_g$ , Low Intrinsic  $R_g$   
High  $dV/dt$ , Low  $t_{rr}$

$V_{DSS} = 1000 \text{ V}$

$I_{D25} = 38 \text{ A}$

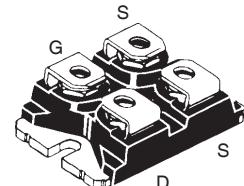
$R_{DS(on)} = 0.25 \Omega$

$t_{rr} \leq 300 \text{ ns}$



Preliminary Data Sheet

miniBLOC, SOT-227 B (IXFN)  
 E153432



G = Gate                      D = Drain  
S = Source

Either Source terminal at miniBLOC can be used as Main or Kelvin Source

Symbol	Test Conditions	Maximum Ratings		
$V_{DSS}$	$T_J = 25^\circ\text{C}$ to $150^\circ\text{C}$	1000		V
$V_{DGR}$	$T_J = 25^\circ\text{C}$ to $150^\circ\text{C}$ ; $R_{GS} = 1 \text{ M}\Omega$	1000		V
$V_{GS}$	Continuous	$\pm 30$		V
$V_{GSM}$	Transient	$\pm 40$		V
$I_{D25}$	$T_c = 25^\circ\text{C}$	38		A
$I_{DM}$	$T_c = 25^\circ\text{C}$ , pulse width limited by $T_{JM}$	152		A
$I_{AR}$	$T_c = 25^\circ\text{C}$	38		A
$E_{AR}$	$T_c = 25^\circ\text{C}$	60		mJ
$E_{AS}$	$T_c = 25^\circ\text{C}$	5.0		J
$dv/dt$	$I_s \leq I_{DM}$ , $dv/dt \leq 100 \text{ A}/\mu\text{s}$ , $V_{DD} \leq V_{DSS}$ $T_J \leq 150^\circ\text{C}$ , $R_G = 2 \Omega$	20		V/ns
$P_D$	$T_c = 25^\circ\text{C}$	890		W
$T_J$		-55 ... +150		$^\circ\text{C}$
$T_{JM}$		150		$^\circ\text{C}$
$T_{stg}$		-55 ... +150		$^\circ\text{C}$
$V_{ISOL}$	50/60 Hz, RMS, $t = 1$ minute	2500		V
$M_d$	Mounting torque Terminal connection torque	1.5/13	Nm/lb.in.	
Weight		30		g

Symbol	Test Conditions	Characteristic Values		
		( $T_J = 25^\circ\text{C}$ , unless otherwise specified)	min.	typ.
$V_{DSS}$	$V_{GS} = 0 \text{ V}$ , $I_D = 1 \text{ mA}$	1000		V
$V_{GS(th)}$	$V_{DS} = V_{GS}$ , $I_D = 8 \text{ mA}$	2.5		5.0 V
$I_{GSS}$	$V_{GS} = \pm 30 \text{ V}$ , $V_{DS} = 0$			$\pm 200 \text{ nA}$
$I_{DSS}$	$V_{DS} = V_{DSS}$ $V_{GS} = 0 \text{ V}$	$T_J = 25^\circ\text{C}$ $T_J = 125^\circ\text{C}$		50 mA 3 mA
$R_{DS(on)}$	$V_{GS} = 10 \text{ V}$ , $I_D = 0.5 \cdot I_{D25}$ Note 1			0.25 $\Omega$

## Features

- Double metal process for low gate resistance
- miniBLOC, with Aluminium nitride isolation
- Unclamped Inductive Switching (UIS) rated
- Low package inductance
- Fast intrinsic Rectifier

## Applications

- DC-DC converters
- Switched-mode and resonant-mode power supplies
- DC choppers
- Pulse generators

## Advantages

- Easy to mount
- Space savings
- High power density

Symbol	Test Conditions	Characteristic Values			
		( $T_J = 25^\circ\text{C}$ , unless otherwise specified)	min.	typ.	max.
$g_{fs}$	$V_{DS} = 20 \text{ V}; I_D = 0.5 \cdot I_{D25}$ Note 1	24	40	S	
$C_{iss}$	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$	7200	pF		
$C_{oss}$		950	pF		
$C_{rss}$		170	pF		
$t_{d(on)}$	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 \cdot V_{DSS}, I_D = 0.5 \cdot I_{D25}$ $R_G = 1 \Omega$ (External)	25	ns		
$t_r$		28	ns		
$t_{d(off)}$		57	ns		
$t_f$		15	ns		
$Q_{G(on)}$	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 \cdot V_{DSS}, I_D = 0.5 \cdot I_{D25}$	250	nC		
$Q_{GS}$		60	nC		
$Q_{GD}$		105	nC		
$R_{thJC}$			0.14	K/W	
$R_{thCK}$		0.05		K/W	

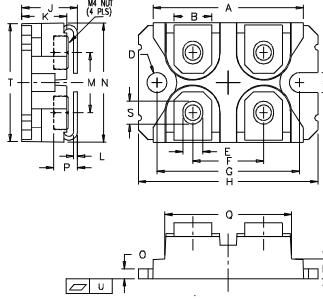
## Source-Drain Diode

Characteristic Values  
( $T_J = 25^\circ\text{C}$ , unless otherwise specified)

Symbol	Test Conditions	Characteristic Values		
		min.	typ.	max.
$I_s$	$V_{GS} = 0 \text{ V}$		38	A
$I_{SM}$	Repetitive; pulse width limited by $T_{JM}$		152	A
$V_{SD}$	$I_F = I_s, V_{GS} = 0 \text{ V}$ , Note 1		1.5	V
$t_{rr}$	$I_F = 25 \text{ A}$ $-di/dt = 100 \text{ A}/\mu\text{s}$ $V_R = 100 \text{ V}$		300	ns
$Q_{RM}$		1.4		$\mu\text{C}$
$I_{RM}$		9		A

Note: 1. Pulse test,  $t \leq 300 \mu\text{s}$ , duty cycle  $d \leq 2 \%$ 

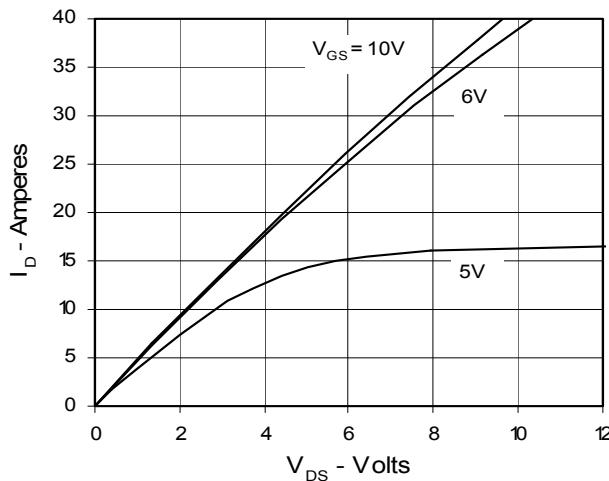
## miniBLOC, SOT-227 B Outline



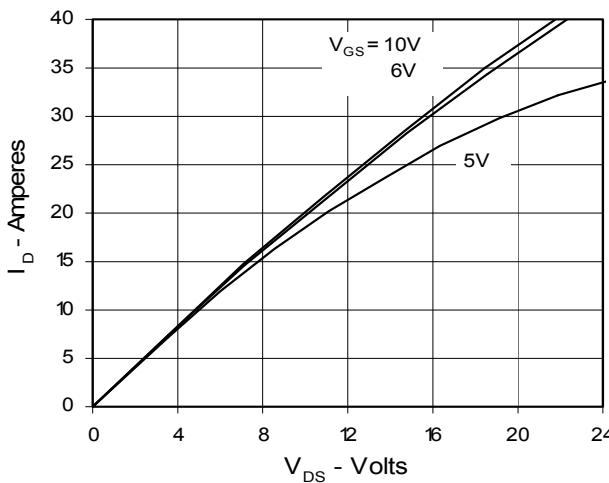
M4 screws (4x) supplied

Dim.	Millimeter		Inches	
	Min.	Max.	Min.	Max.
A	31.50	31.88	1.240	1.255
B	7.80	8.20	0.307	0.323
C	4.09	4.29	0.161	0.169
D	4.09	4.29	0.161	0.169
E	4.09	4.29	0.161	0.169
F	14.91	15.11	0.587	0.595
G	30.12	30.30	1.186	1.193
H	38.00	38.23	1.496	1.505
J	11.68	12.22	0.460	0.481
K	8.92	9.60	0.351	0.378
L	0.76	0.84	0.030	0.033
M	12.60	12.85	0.496	0.506
N	25.15	25.42	0.990	1.001
O	1.98	2.13	0.078	0.084
P	4.95	5.97	0.195	0.235
Q	26.54	26.90	1.045	1.059
R	3.94	4.42	0.155	0.174
S	4.72	4.85	0.186	0.191
T	24.59	25.07	0.968	0.987
U	-0.05	0.1	-0.002	0.004

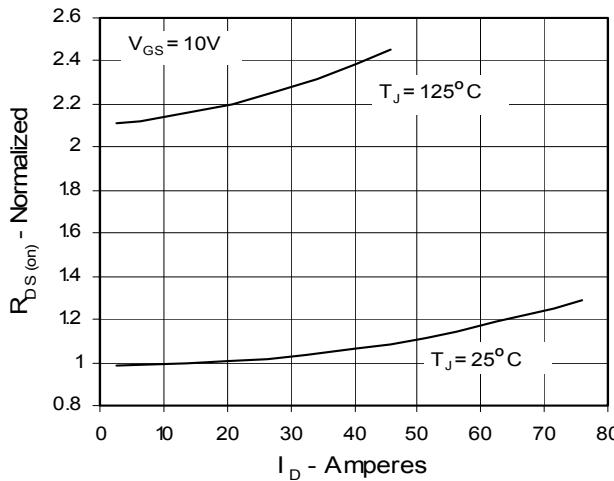
**Fig. 1. Output Characteristics  
@ 25 Deg. C**



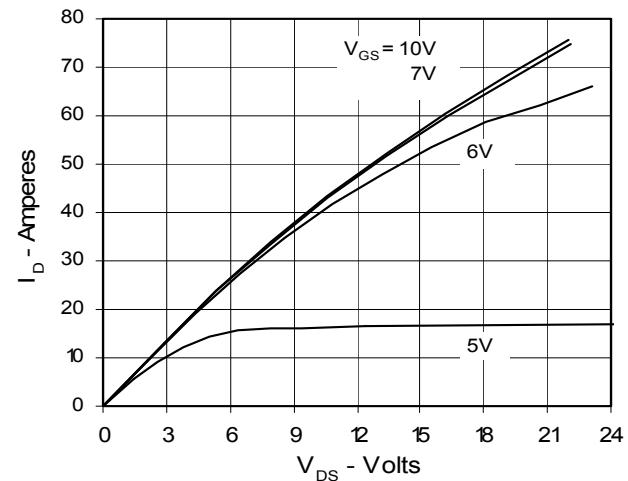
**Fig. 3. Output Characteristics  
@ 125 Deg. C**



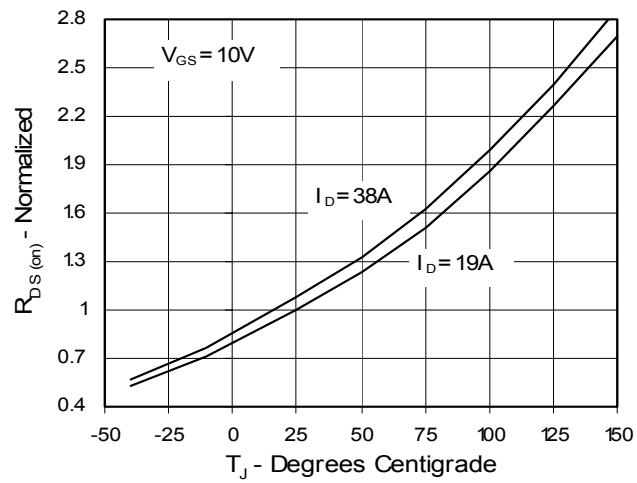
**Fig. 5.  $R_{DS(on)}$  Normalized to  $I_{D25}$   
Value vs.  $I_D$**



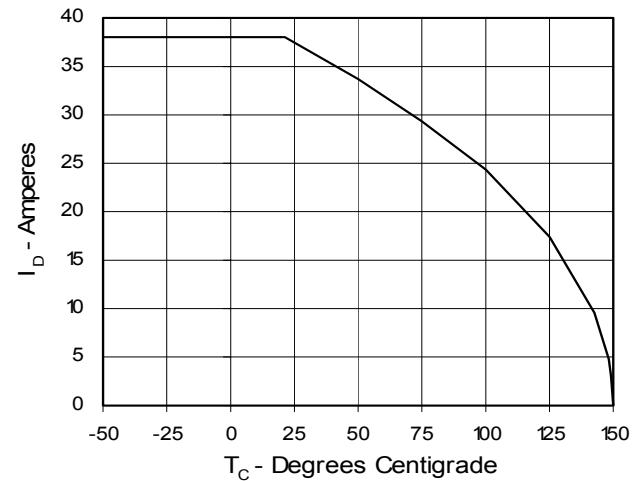
**Fig. 2. Extended Output Characteristics  
@ 25 deg. C**

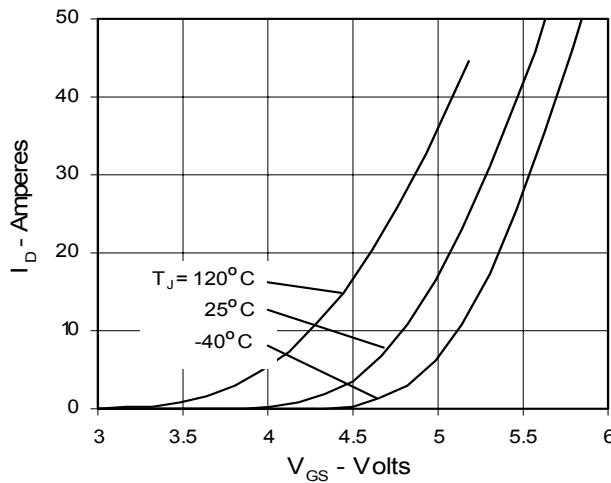
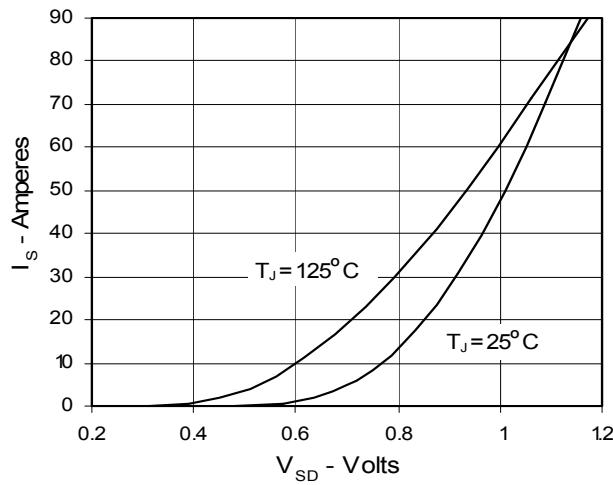
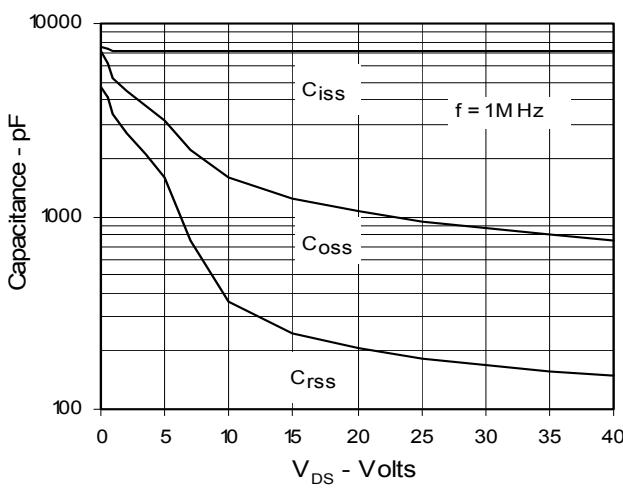


**Fig. 4.  $R_{DS(on)}$  Normalized to  $I_{D25}$  Value vs.  
Junction Temperature**



**Fig. 6. Drain Current vs. Case  
Temperature**

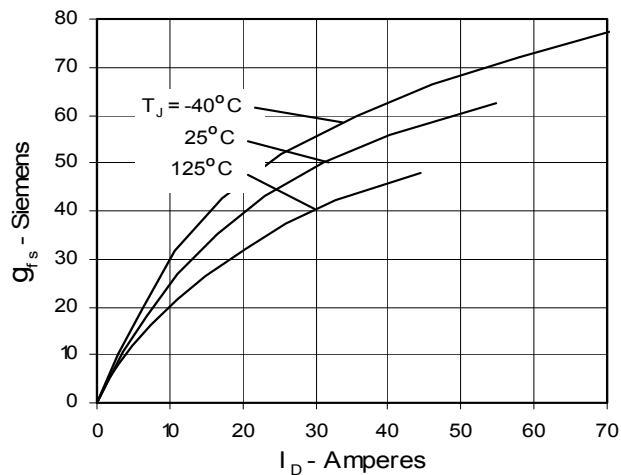
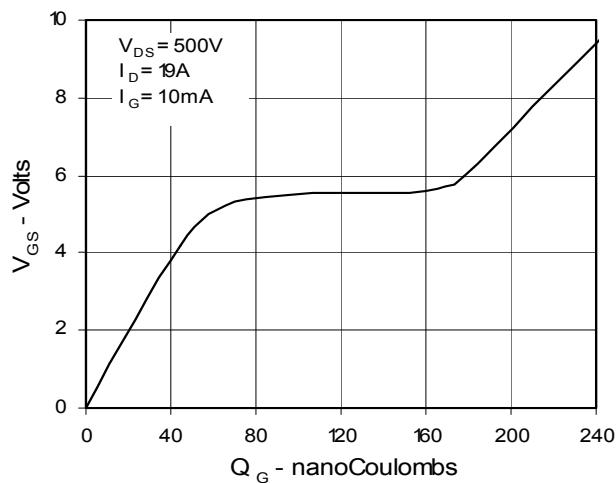


**Fig. 7. Input Admittance**

**Fig. 9. Source Current vs. Source-To-Drain Voltage**

**Fig. 11. Capacitance**


IXYS reserves the right to change limits, test conditions, and dimensions.

IXYS MOSFETs and IGBTs are covered by one or more of the following U.S. patents:

4,835,592 4,881,106 5,017,508 5,049,961 5,187,117 5,486,715 6,306,728B1 6,259,123B1 6,306,728B1  
4,850,072 4,931,844 5,034,796 5,063,307 5,237,481 5,381,025 6,404,065B1 6,162,665 6,534,343

**Fig. 8. Transconductance**

**Fig. 10. Gate Charge**

**Fig. 12. Maximum Transient Thermal Resistance**
